

<b>FORM HDP-1449 (Based on Form PTO-1449)</b>  <b>PATENT AND TRADEMARK OFFICE</b> <b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary)  Sheet 1 of 1	ATTORNEY DOCKET No.	SERIAL No.
	2115-002431	10/603,051
	APPLICANT	
	Segall et al.	
	FILING DATE	GROUP
	June 24, 2003	Unassigned

### U.S. PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.	MS	4,334,780	06/15/1982	Pernick	—	—
2.	MS	5,189,490	02/23/1993	Shetty et al.	—	—
3.	MS	6,084,671	07/04/2000	Holcomb	—	—
4.	MS	6,567,162 B2	05/20/2003	Koren et al.	—	—

### FOREIGN PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation	
						Yes	No
1.							

### OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)

Ref. Desig.	Examiner's Initials	
1.	MS	G.J. Dixon; Light Scattering Maps Surface Imperfections; Optical Engineering: Surface Scattering; Laser Focus World; www.optoelectronics-world.com; November 1998; pp. 89 - 94.
2.	MS	SMS; A New Light on Quality; Interpreting Light Scatter Measurements; Schmitt Measurement Systems, Inc.; April 1994; pp. 1 - 19.
3.	MS	Thomas A. Germer et al.; Polarized Light Scattering Measurements of Polished and Etched Steel Surfaces; Scattering and Surface Roughness III, Z.-H Gu, and A.A. Maradudin, Eds., Proc. SPIE 4100, 148 - 155 (2000).
4.	MS	Cz. Lukianowicz, et al.; Optical System for Measurement of Surface Form and Roughness; Measurement Science Review, Vol. 1, Number 1, 2001; pp. 151 - 154.

Examiner: <u>Michael Stefan</u>	Date Considered: <u>3-15-05</u>
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EXAMINER: Please initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.